



經歷：

- ◆ 開南大學教務長(2021.8-2022.7)
- ◆ 開南大學代理教務長(2021.2-2021.7)
- ◆ 開南大學副教務長(2018.8-2021.7)
- ◆ 開南大學註冊課務組組長(2017.8-2018.6)
- ◆ 開南大學交通運輸系系主任(2019.8-2020.7)

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